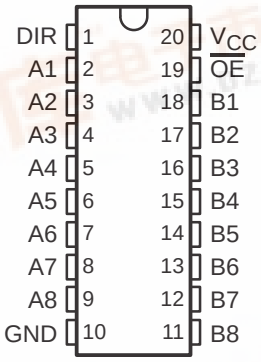
SN54ALS1245A, SN74ALS1245A
OCTAL BUS TRANSCEIVERS WITH 3-STATE OUTPUTS

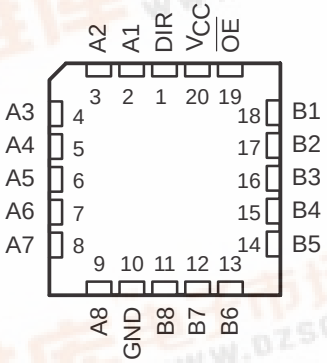
SDAS245A – DECEMBER 1982 – REVISED JANUARY 1995

- **Bidirectional Bus Transceivers in High-Density 20-Pin Packages**
- **Low-Power Versions of ′ALS245 Series**
- **′ALS1245 Series Is Identical to ′ALS1645 Series**
- **Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs**

SN54ALS1245A . . . J PACKAGE
SN74ALS1245A . . . DW OR N PACKAGE
(TOP VIEW)



SN54ALS1245A . . . FK PACKAGE
(TOP VIEW)



description

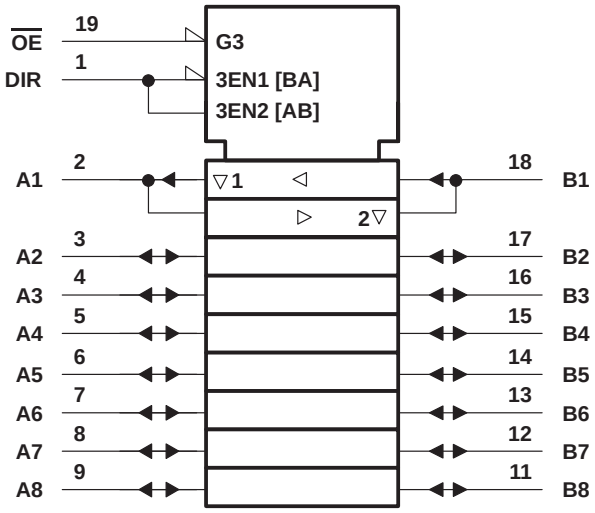
These octal bus transceivers are designed for asynchronous two-way communication between data buses. These devices transmit data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable ($\overline{OE}$) input can be used to disable the device so the buses are effectively isolated.

The SN54ALS1245A is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ALS1245A is characterized for operation from 0°C to 70°C.

FUNCTION TABLE

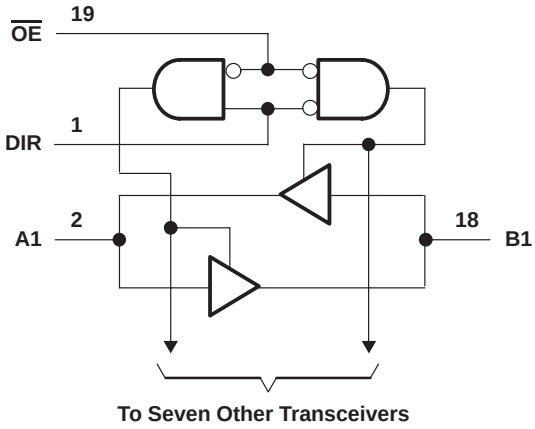
INPUTS		OPERATION
$\overline{OE}$	DIR	
L	L	B data to A bus
L	H	A data to B bus
H	X	Isolation

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V_{CC} . . . . . 7 V
Input voltage, V_I: All inputs . . . . . 7 V
I/O ports . . . . . 5.5 V
Operating free-air temperature range, T_A: SN54ALS1245A . . . . . –55°C to 125°C
SN74ALS1245A . . . . . 0°C to 70°C
Storage temperature range . . . . . –65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54ALS1245A			SN74ALS1245A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.7			0.8	V
I_{OH}	High-level output current			–12			–15	mA
I_{OL}	Low-level output current			8			16	mA
T_A	Operating free-air temperature	–55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN54ALS1245A			SN74ALS1245A			UNIT
				MIN	TYP†	MAX	MIN	TYP†	MAX	
V_{IK}		V_{CC} = 4.5 V,	I_I = –18 mA			–1.5			–1.5	V
V_{OH}		V_{CC} = 4.5 V to 5.5 V,	I_{OH} = –0.4 mA	V_{CC} –2			V_{CC} –2			V
		V_{CC} = 4.5 V	I_{OH} = –3 mA	2.4	3.2		2.4	3.2		
			I_{OH} = –12 mA	2						
			I_{OH} = –15 mA				2			
V_{OL}		V_{CC} = 4.5 V	I_{OL}= 8 mA		0.25	0.4		0.25	0.4	V
			I_{OL} = 16 mA					0.35	0.5	
I_I	Control inputs	V_{CC} = 5.5 V	V_I = 7 V			0.1			0.1	mA
	A or B ports		V_I = 5.5 V			0.1			0.1	
I_{IH}	Control inputs	V_{CC} = 5.5 V,	V_I = 2.7 V			20			20	µA
	A or B ports‡					20			20	
I_{IL}	Control inputs	V_{CC} = 5.5 V,	V_I = 0.4 V			–0.1			–0.1	mA
	A or B ports‡					–0.1			–0.1	
I_O§		V_{CC} = 5.5 V,	V_O = 2.25 V	–20		–112	–30		–112	mA
I_{CC}		V_{CC} = 5.5 V	Outputs high		21	33		21	30	mA
			Outputs low		23	36		23	33	
			Outputs disabled		25	40		25	36	

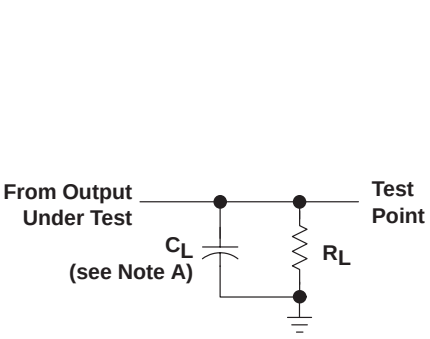
† All typical values are V_{CC} = 5 V, T_A = 25°C.
‡ For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.
§ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS}.

switching characteristics (see Figure 1)

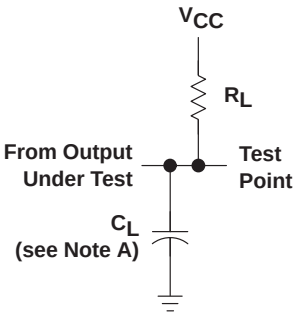
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R1 = 500 Ω, R2 = 500 Ω, T_A = MIN to MAX¶				UNIT
			SN54ALS1245A		SN74ALS1245A		
			MIN	MAX	MIN	MAX	
t_{PLH}	A or B	B or A	2	19	2	13	ns
t_{PHL}			2	15	2	13	
t_{PZH}	$\overline{OE}$	A or B	8	30	8	25	ns
t_{PZL}			8	29	8	25	
t_{PHZ}	$\overline{OE}$	A or B	2	14	2	12	ns
t_{PLZ}			3	30	3	18	

¶ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

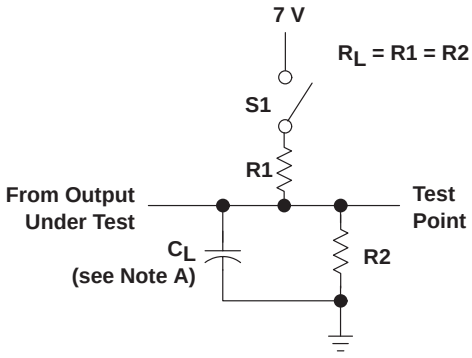
PARAMETER MEASUREMENT INFORMATION
SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



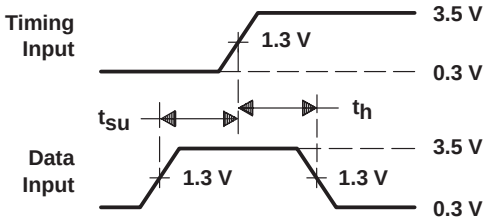
LOAD CIRCUIT FOR
BI-STATE
TOTEM-POLE OUTPUTS



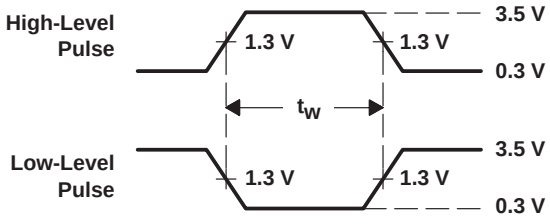
LOAD CIRCUIT
FOR OPEN-COLLECTOR OUTPUTS



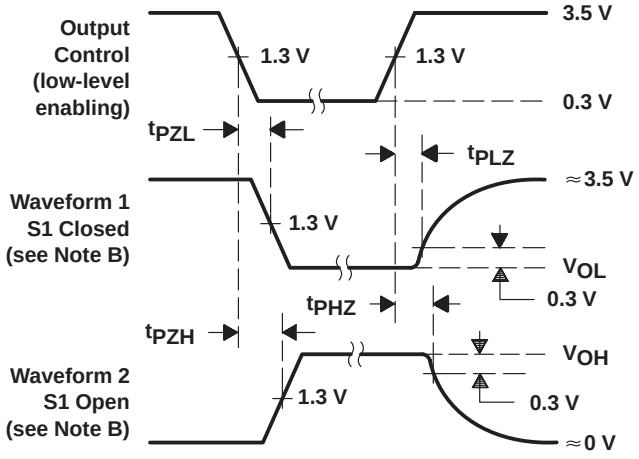
LOAD CIRCUIT
FOR 3-STATE OUTPUTS



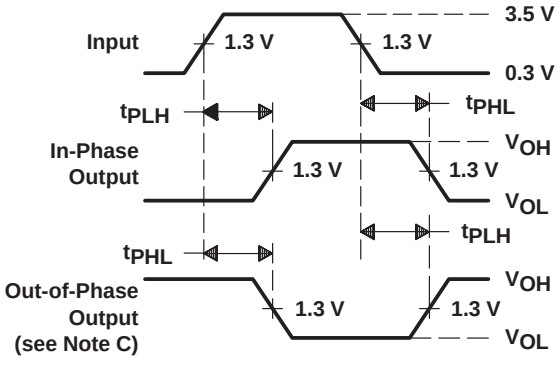
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PULSE DURATIONS



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
D. All input pulses have the following characteristics: PRR ≤ 1 MHz, $t_r = t_f$ = 2 ns, duty cycle = 50%.
E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms

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